

Notice of References Cited		Application/Control No. 09/834,591	Applicant(s)/Patent Under Reexamination BARKER ET AL.	
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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-4,731,785	03-1988	Ferenc et al.	370/537
B	US-6,385,208	05-2002	Findlater et al.	370/419
C	US-6,795,881	09-2004	Bachrach, Yuval	710/100
D	US-6,651,107	11-2003	Conley et al.	709/250
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